

Search Notes**Application/Control No.**

09/512,276

Examiner

Louis K. Huynh

Applicant(s)/Patent under Reexamination

NAGAO ET AL.

Art Unit

3721

SEARCHED

Class	Subclass	Date	Examiner
206	408 446 522 591 594	4/16/2002	LT
53	472 449	4/16/2002	LT
Updated	All above	2/4/2003	LT
53	139.5 49	11/22/2005	LH
53	449 444 409	11/22/2005	LH
206	419 421	11/28/2005	LH
Updated	All above	12/22/2005	LH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted with John Sipos (class 53) David Fidei (class 206)	4/16/2002	LT
EAST text search "glass base material"	2/11/2003	LT